

# Device Modeling Report

COMPONENTS:PHOTOCOUPLER  
PART NUMBER:PC357NT  
MANUFACTURER: SHARP



**Bee Technologies Inc.**

## DIODE MODEL

Pspice model Parameter	Model description
IS	Saturation Current
N	Emission Coefficient
RS	Series Resistance
IKF	High-injection Knee Current
CJO	Zero-bias Junction Capacitance
M	Junction Grading Coefficient
VJ	Junction Potential
ISR	Recombination Current Saturation Value
BV	Reverse Breakdown Voltage(a positive value)
IBV	Reverse Breakdown Current(a positive value)
TT	Transit Time

## BIPOLAR JUNCTION TRANSISTOR MODEL

Pspice model parameter	Model description
NR	Reverse Emission Coefficient
RB	Base Resistance
RC	Series Collector Resistance
CJE	Zero-bias Emitter-Base Junction Capacitance
CJC	Zero-bias Collector-Base Junction Capacitance
TF	Forward Transit Time
TR	Reverse Transit Time

## VOLTAGE CONTROLLED VOLTAGE SOURCE MODEL(VCVS)

E<Name><(+)Node><(-)Node>VALUE={Expression}

E<Name><(+)Node><(-)Node>TABLE={Expression}

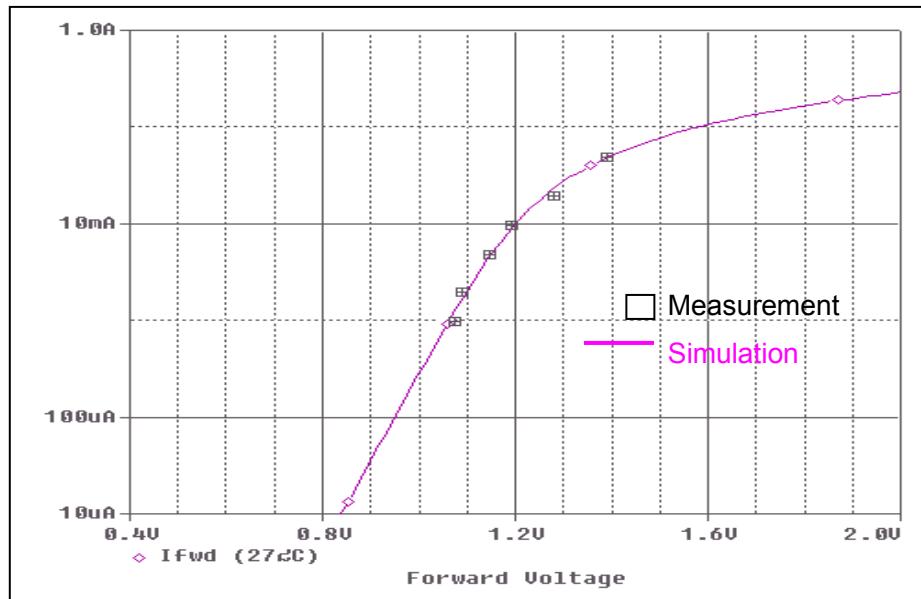
## **VOLTAGE CONTROLLED CURRENT SOURCE MODEL(VCCS)**

E<Name><(+)Node><(−)Node>VALUE={Expression}

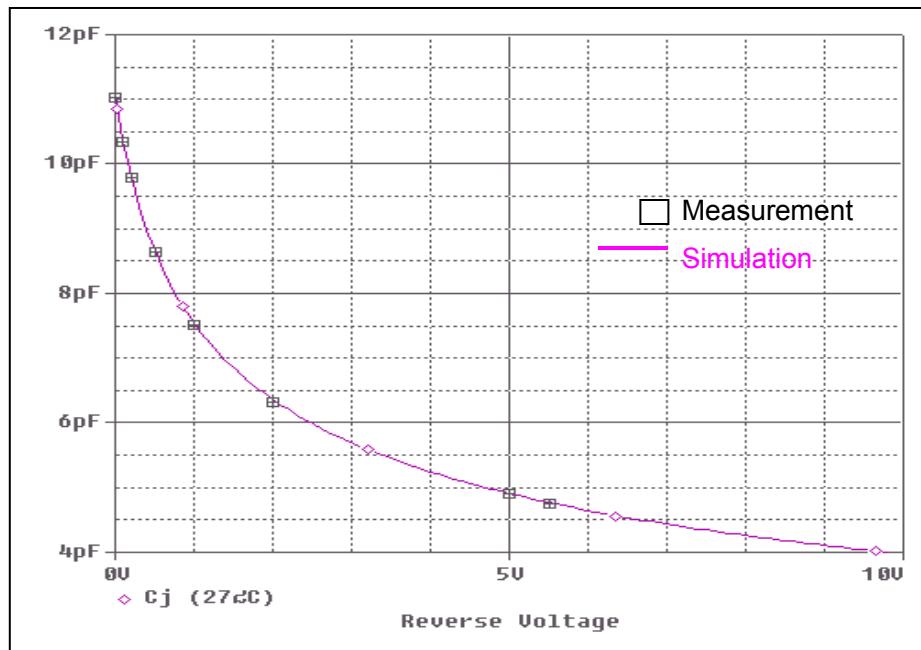
### **CURRENT CONTROLLED MODEL(W)**

Pspice model parameter	Model description
IOFF	Controlling current to Off state
ION	Controlling current to On state
ROFF	Off Resistance
RON	On Resistance

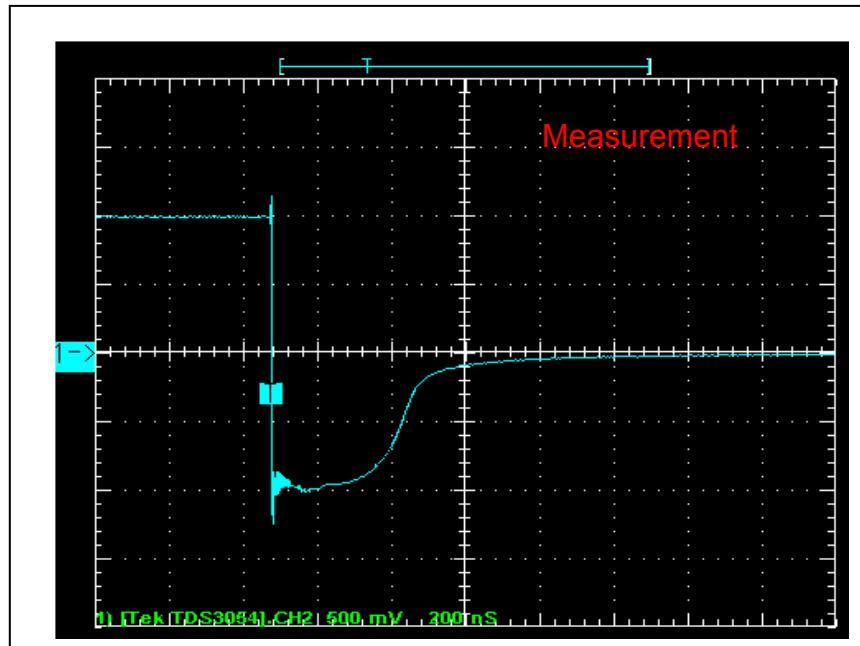
## Input Device Forward Current Characteristics



## Input Device Junction Capacitance Characteristics



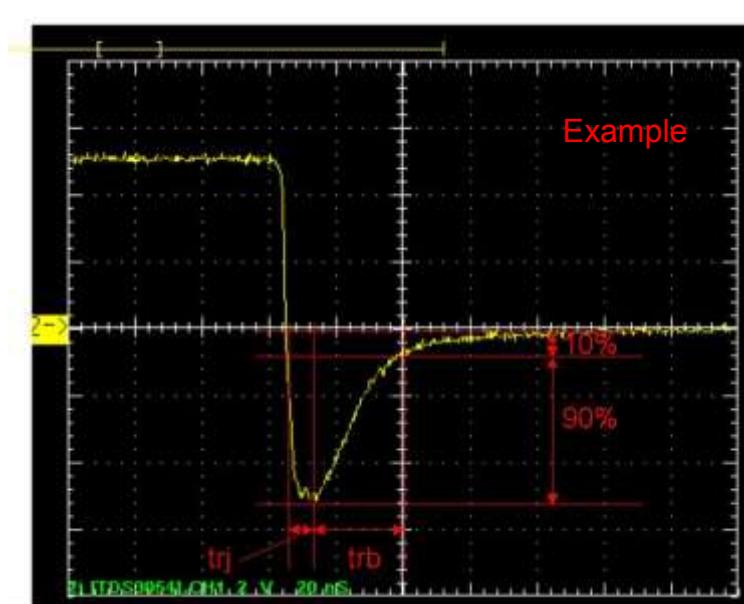
## Input Device Reverse Recovery Characteristics



trj=228n(s)

trb=300n(s)

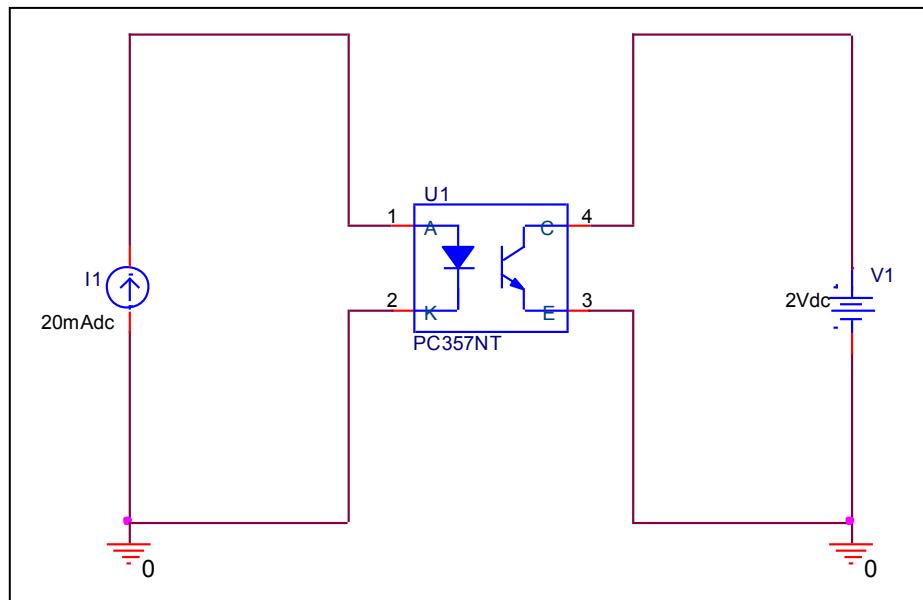
Conditions: Ifwd=Irev=0.04(A), RI=50



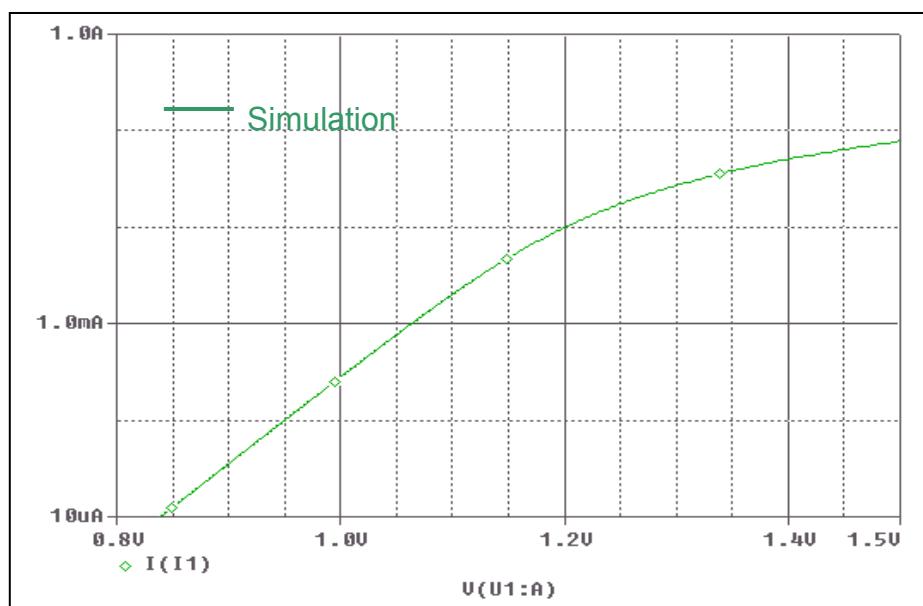
Relation between trj and trb

## LED IV Curve Characteristics

Evaluation Circuit



Simulation result

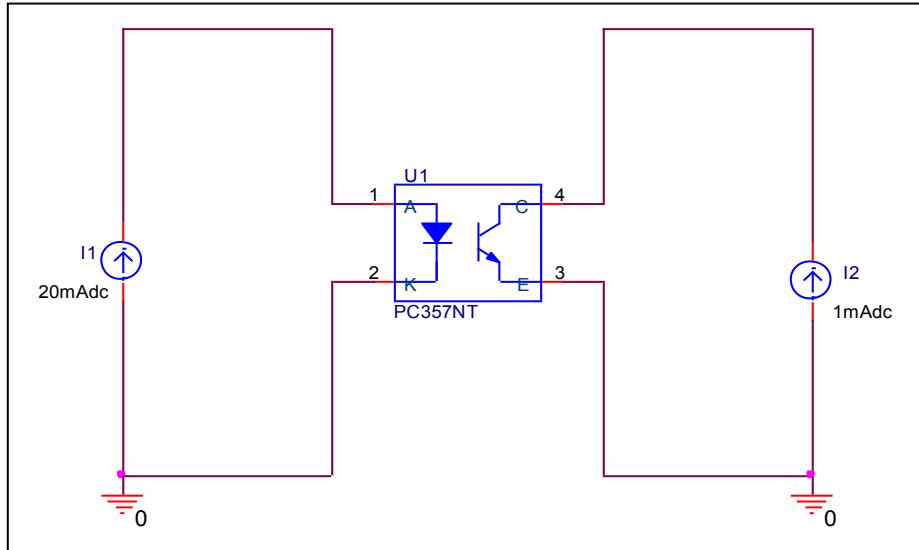


## Comparison Table

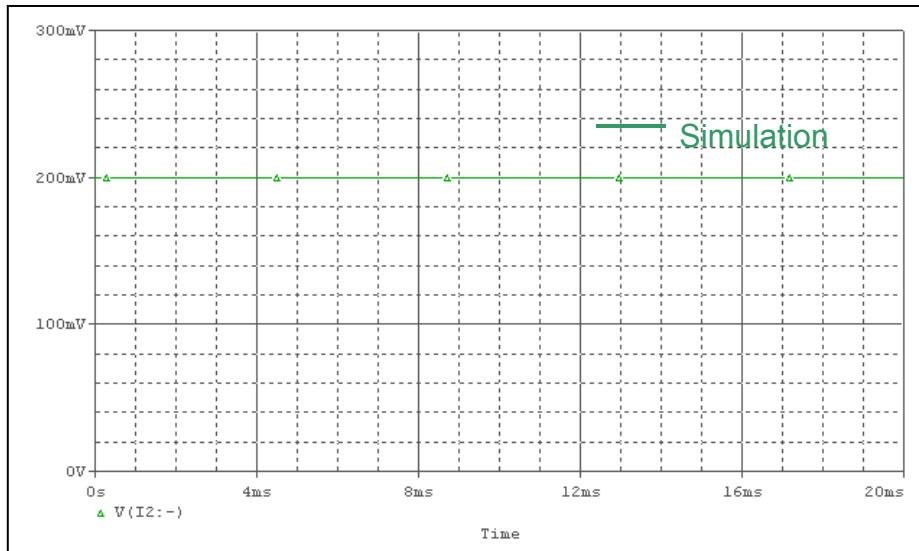
Ifwd(A)	Vfwd(V)		% Error
	Measurement	Simulation	
0.001	1.074	1.0632	-1.006
0.002	1.089	1.0995	0.964
0.005	1.148	1.1524	0.383
0.01	1.192	1.2006	0.721
0.02	1.281	1.2635	-1.366
0.05	1.392	1.3966	0.330

## Transistor Saturation Characteristics

Evaluation Circuit



Simulation result

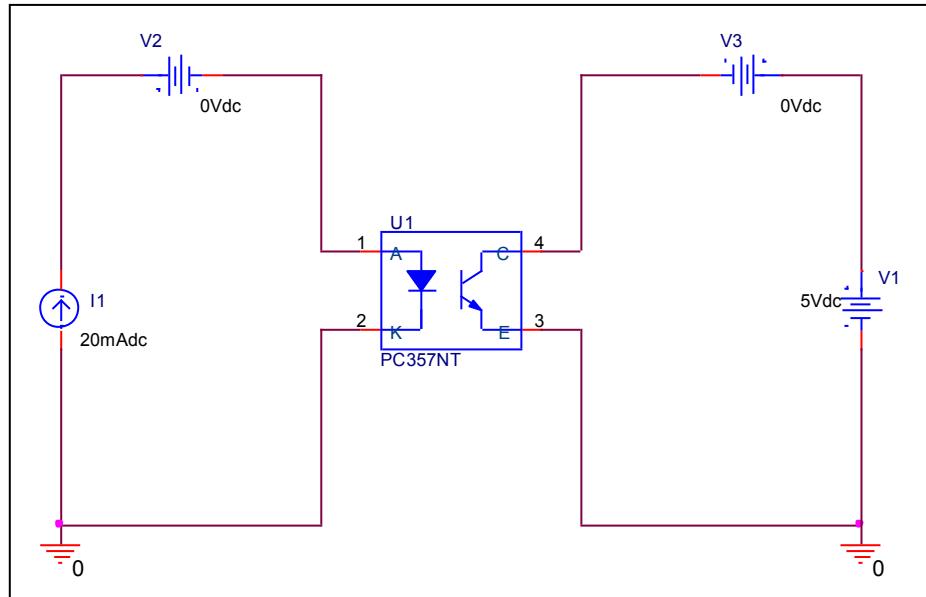


Comparison Table

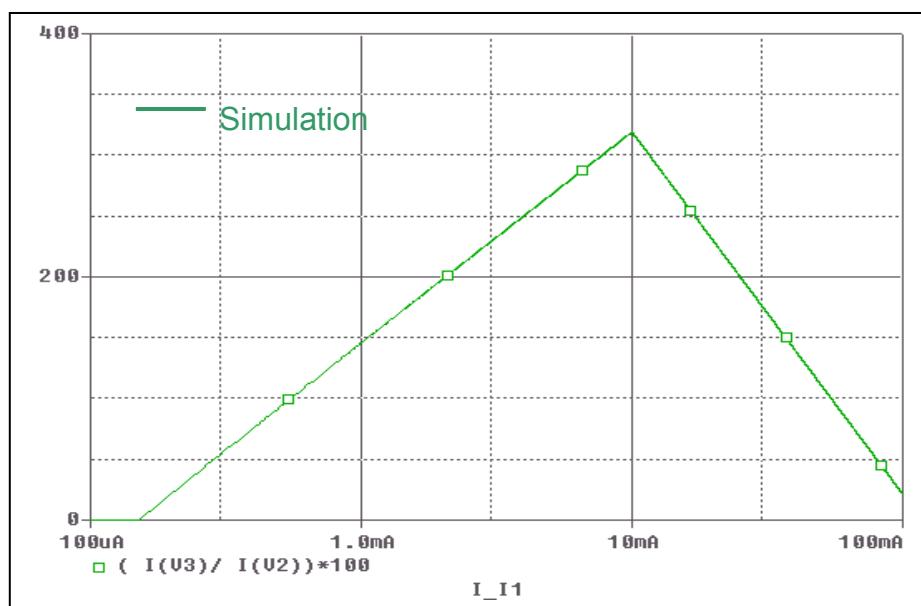
	Measurement	Simulation	% Error
$V_{ce(\text{sat})}$ (V)	0.2	0.199	-0.5

## CTR(Current Transfer Ratio) Characteristics

Evaluation Circuit



Simulation result



## Rise Curve Table

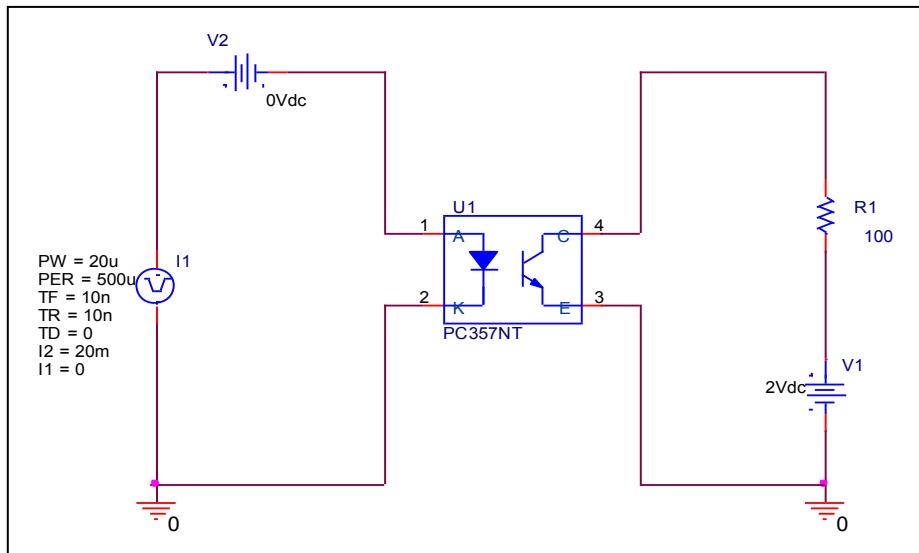
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
1	145	149.626	3.190
2	210	200.635	-4.460
4	260	251.413	-3.303
6	290	281.021	-3.096
9	311	310.547	-0.146
10	318.7	318.13	-0.179

## Fall Curve Table

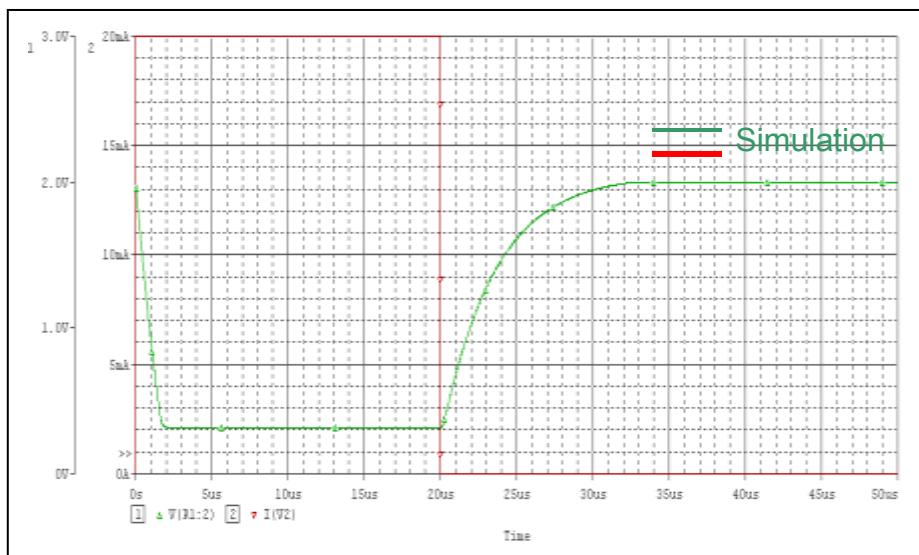
If(mA)	CTR(%)		% Error
	Measurement	Simulation	
10	318.70	318.13	-0.179
20	240.00	228.263	-4.890
30	175.00	176.612	0.921
40	140.00	139.994	-0.004
50	115.00	111.607	-2.950

## Switching Time Characteristics

Evaluation Circuit



Simulation result



Comparison Table

$V_{cc}=2V, IC=2mA, RL=100\Omega$	Measurement	Simulation	% Error
Ts (us)	0.48	0.487353	1.532
Tf (us)	6.9	6.8875	-0.181